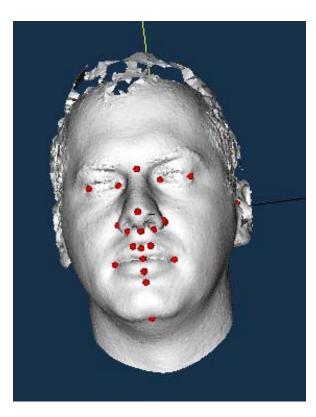
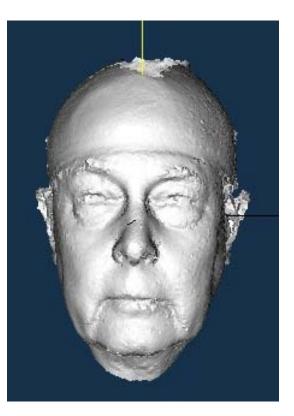
Landmark Locating using Deformable Registration

Jia Wu Course Project EE 577 December 12, 2011

Problem Statement



Example mesh Landmarks on it

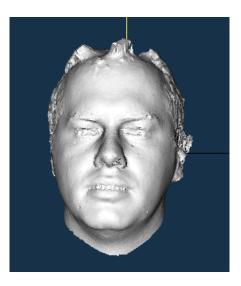


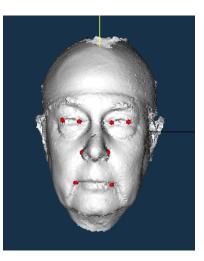
Given a new mesh, where are the landmarks?

Method: Deformable transformation



Deformable transform





Overview (Allen's paper)

- Goal: to fit a template surface \mathcal{T} to a scanned example surface \mathcal{D} .
- Each surface is represented as a triangular mesh
- The matching is accomplished by an optimization framework
- Each vertex v_i is influenced by a 4 x 4 affine transformation matrix T_i.
- The algorithm must find a set of transformations that move all of the points in \mathcal{T} to a deformed surface \mathcal{T} such that \mathcal{T} matches well with \mathcal{D} .

Energy Function: $E = \alpha E_d + \beta E_s + \gamma E_m$

data error

$$E_d = \sum_{i=1}^n w_i \operatorname{dist}^2(\mathbf{T}_i \mathbf{v}_i, \mathcal{D}), \qquad (1)$$

where dist() computes the distances from T_iv_i to the closest compatible point on \mathcal{D} , where compatible means the surface normals are no more than 90 degrees apart, and the distance is less than a threshold.

smoothness
$$E_s = \sum_{\{i,j|\{\mathbf{v}_i,\mathbf{v}_j\}\in edges(\mathcal{T})\}} ||\mathbf{T}_i - \mathbf{T}_j||_F^2$$
(2)

where $|| ||_{F}$ is the Frobenius norm and measures the distance between transformations.

marker error
(if markers)
$$E_m = \sum_{i=1}^m ||\mathbf{T}_{\kappa_i} \mathbf{v}_{\kappa_i} - \mathbf{m}_i||^2 \qquad (3)$$

Procedure

At low resolution

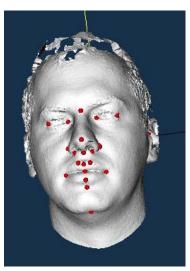
- 1. Fit the markers first: α =0, β =1, γ =10
- 2. Allow the data term to contribute: $\alpha = 1$, $\beta = 1$, $\gamma = 10$

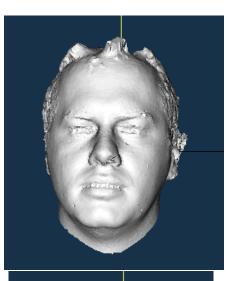
At high resolution

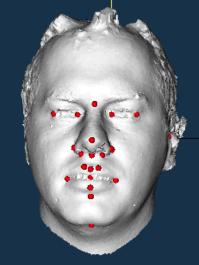
- 3. Continue the optimization: α =1, β =1, γ =10
- 4. Allow the data term to dominate: α =10, β =1, γ =1

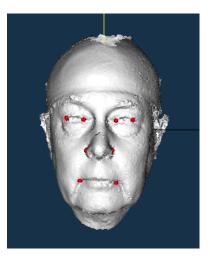
Method: Deformable transformation

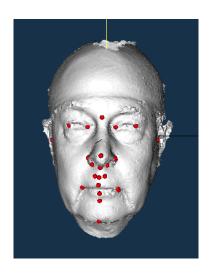












Landmark transfer result

